 arch Note	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/661,736	LAI, CHUAN DE
Examiner	Art Unit
Richard H. Kim	2871

	SEAR	CHED	
Class	Subclass	Date	Examiner
362	27,31,559, 560,561	5/23/2005	RHK
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INT	ERFERENC	RENCE SEARCHED	
Class	Subclass	Date	Examiner

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
XMR	DATE EX		
RHK	5/23/2005 RF	Search	
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